

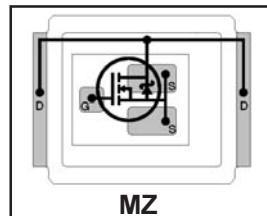
IRF6668PbF IRF6668TRPbF

- RoHs Compliant ①
- Lead-Free (Qualified up to 260°C Reflow)
- Application Specific MOSFETs
- Ideal for High Performance Isolated Converter Primary Switch Socket
- Optimized for Synchronous Rectification
- Low Conduction Losses
- High CdV/dt Immunity
- Low Profile (<0.7mm)
- Dual Sided Cooling Compatible ①
- Compatible with existing Surface Mount Techniques ①

DirectFET™ Power MOSFET ②

Typical values (unless otherwise specified)

V_{DSS}	V_{GS}	$R_{DS(on)}$			
80V max	$\pm 20V$ max	12mΩ@ 10V			
$Q_{g\text{ tot}}$	Q_{gd}	Q_{gs2}	Q_{rr}	Q_{oss}	$V_{gs(\text{th})}$
22nC	7.8nC	1.6nC	40nC	12nC	4.0V



Applicable DirectFET Outline and Substrate Outline (see p.7,8 for details) ①

SQ	SX	ST	MQ	MX	MT	MZ		
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Description

The IRF6668PbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET™ packaging to achieve the lowest on-state resistance in a package that has the footprint of a SO-8 and only 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques. Application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems, improving previous best thermal resistance by 80%.

The IRF6668PbF is optimized for primary side bridge topologies in isolated DC-DC applications, for 48V(±10%) or 36V-60V ETSI input voltage range systems. The IRF6668PbF is also ideal for secondary side synchronous rectification in regulated isolated DC-DC topologies. The reduced total losses in the device coupled with the high level of thermal performance enables high efficiency and low temperatures, which are key for system reliability improvements, and makes this device ideal for high performance isolated DC-DC converters.

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	80	V
V_{GS}	Gate-to-Source Voltage	± 20	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ④	55	
$I_D @ T_C = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ④	44	A
I_{DM}	Pulsed Drain Current ⑤	170	
E_{AS}	Single Pulse Avalanche Energy ⑥	24	mJ
I_{AR}	Avalanche Current ⑥	23	A

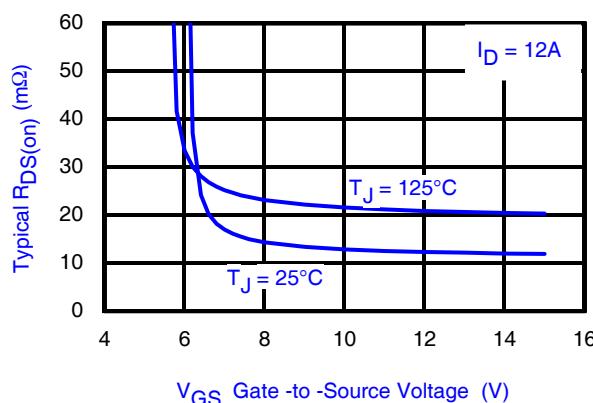


Fig 1. Typical On-Resistance vs. Gate-to-Source Voltage

Notes:

- ① Click on this section to link to the appropriate technical paper.
- ② Click on this section to link to the DirectFET Website.
- ③ Surface mounted on 1 in. square Cu board, steady state.

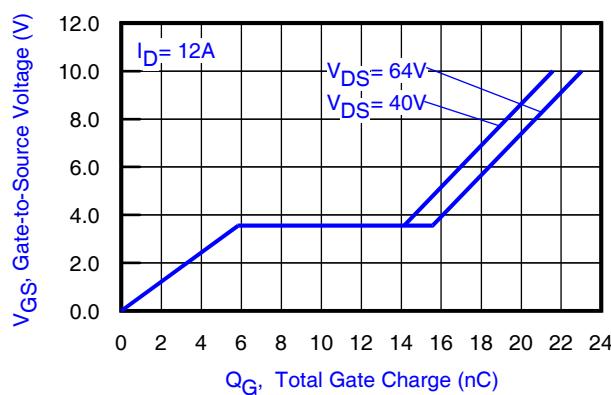


Fig 2. Total Gate Charge vs. Gate-to-Source Voltage

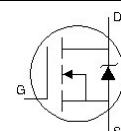
- ④ T_C measured with thermocouple mounted to top (Drain) of part.
- ⑤ Repetitive rating; pulse width limited by max. junction temperature.
- ⑥ Starting $T_J = 25^\circ C$, $L = 0.088mH$, $R_G = 25\Omega$, $I_{AS} = 23A$.

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	80	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.097	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	12	15	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}, I_D = 12\text{A}$ ⑦
$V_{\text{GS(th)}}$	Gate Threshold Voltage	3.0	4.0	4.9	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 100\mu\text{A}$
$\Delta V_{\text{GS(th)}}/\Delta T_J$	Gate Threshold Voltage Coefficient	—	-11	—	mV/ $^\circ\text{C}$	
I_{DSS}	Drain-to-Source Leakage Current	—	—	20	μA	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	250	—	$V_{\text{DS}} = 64\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100	—	$V_{\text{GS}} = -20\text{V}$
g_{fs}	Forward Transconductance	22	—	—	S	$V_{\text{DS}} = 10\text{V}, I_D = 12\text{A}$
Q_g	Total Gate Charge	—	22	31	nC	$V_{\text{DS}} = 40\text{V}$ $V_{\text{GS}} = 10\text{V}$ $I_D = 12\text{A}$ See Fig. 15
$Q_{\text{gs}1}$	Pre-V _{th} Gate-to-Source Charge	—	4.8	—		
$Q_{\text{gs}2}$	Post-V _{th} Gate-to-Source Charge	—	1.6	—		
Q_{gd}	Gate-to-Drain Charge	—	7.8	12		
Q_{godr}	Gate Charge Overdrive	—	7.8	—		
Q_{sw}	Switch Charge ($Q_{\text{gs}2} + Q_{\text{gd}}$)	—	9.4	—	nC	$V_{\text{DS}} = 16\text{V}, V_{\text{GS}} = 0\text{V}$
Q_{oss}	Output Charge	—	12	—		
$R_{\text{G(Internal)}}$	Gate Resistance	—	1.0	—		
$t_{\text{d(on)}}$	Turn-On Delay Time	—	19	—		
t_r	Rise Time	—	13	—	ns	$V_{\text{DD}} = 40\text{V}, V_{\text{GS}} = 10\text{V}$ ⑦ $I_D = 12\text{A}$ $R_G = 6.2\Omega$ See Fig. 16 & 17
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	7.1	—		
t_f	Fall Time	—	23	—		
C_{iss}	Input Capacitance	—	1320	—	pF	$V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 25\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	310	—		
C_{rss}	Reverse Transfer Capacitance	—	76	—		

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_s	Continuous Source Current (Body Diode)	—	—	81	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ⑤	—	—	170		
V_{SD}	Diode Forward Voltage	—	—	1.3		
t_{rr}	Reverse Recovery Time	—	34	51	ns	$T_J = 25^\circ\text{C}, I_F = 12\text{A}$
Q_{rr}	Reverse Recovery Charge	—	40	60	nC	di/dt = 100A/ μs ⑦ See Fig. 18

**Notes:**

⑤ Repetitive rating; pulse width limited by max. junction temperature.

⑦ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.

Absolute Maximum Ratings

	Parameter	Max.	Units
P _D @ T _A = 25°C	Power Dissipation ③	2.8	W
P _D @ T _A = 70°C	Power Dissipation ③	1.8	
P _D @ T _C = 25°C	Power Dissipation ④	89	
T _P	Peak Soldering Temperature	270	°C
T _J	Operating Junction and Storage Temperature Range	-40 to + 150	
T _{STG}			

Thermal Resistance

	Parameter	Typ.	Max.	Units
R _{θJA}	Junction-to-Ambient ③ ⑩	—	45	
R _{θJA}	Junction-to-Ambient ⑨ ⑩	12.5	—	
R _{θJA}	Junction-to-Ambient ⑩ ⑩	20	—	°C/W
R _{θJC}	Junction-to-Case ④ ⑩	—	1.4	
R _{θJ-PCB}	Junction-to-PCB Mounted	1.0	—	
	Linear Derating Factor ③	0.022		W/°C

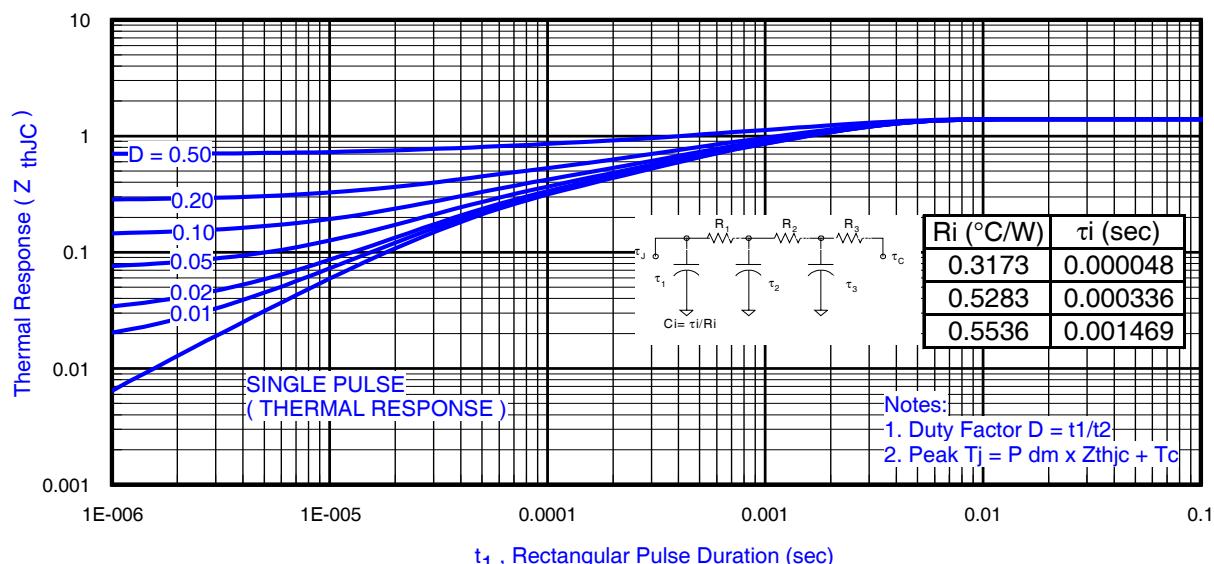


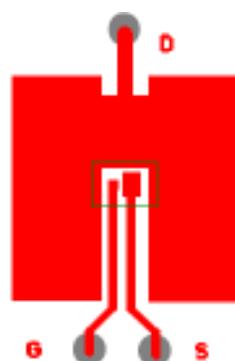
Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

Notes:

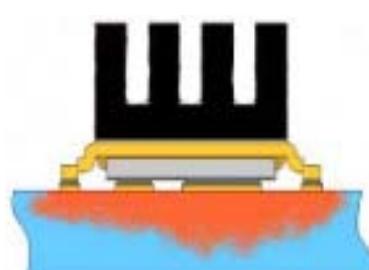
③ Used double sided cooling , mounting pad.

⑩ R_θ is measured at T_j of approximately 90°C.

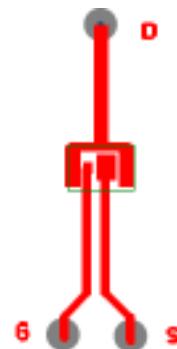
⑩ Mounted on minimum footprint full size board with metalized back and with small clip heatsink.



③ Surface mounted on 1 in. square Cu (still air).



⑩ Mounted to a PCB with small clip heatsink (still air)



⑩ Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air)

IRF6668PbF

International
IR Rectifier

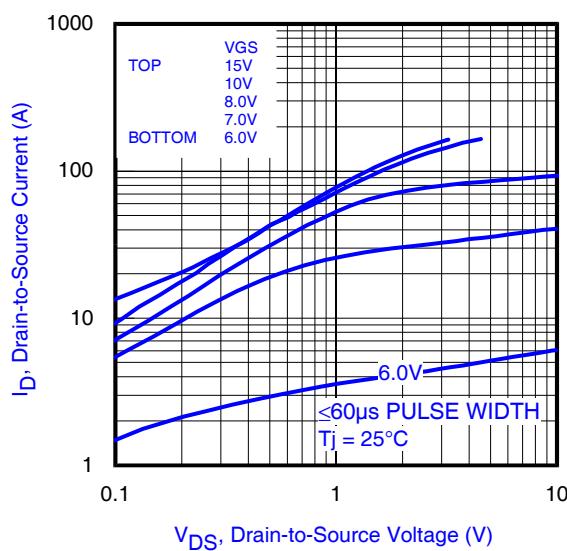


Fig 4. Typical Output Characteristics

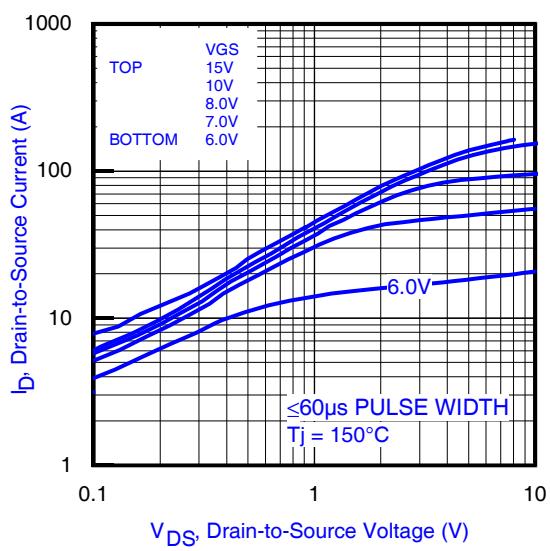


Fig 5. Typical Output Characteristics

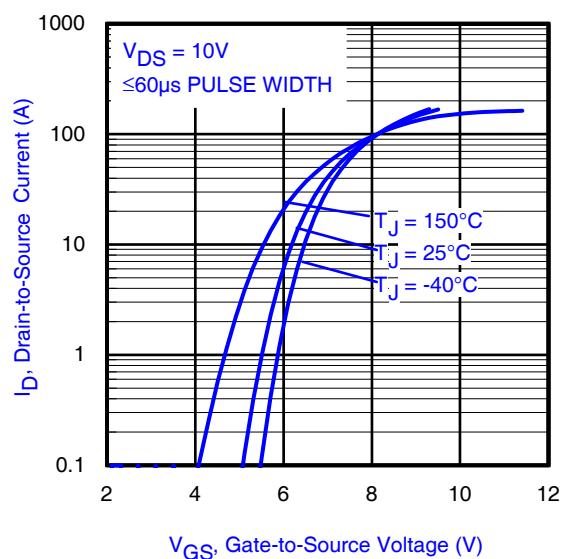


Fig 6. Typical Transfer Characteristics

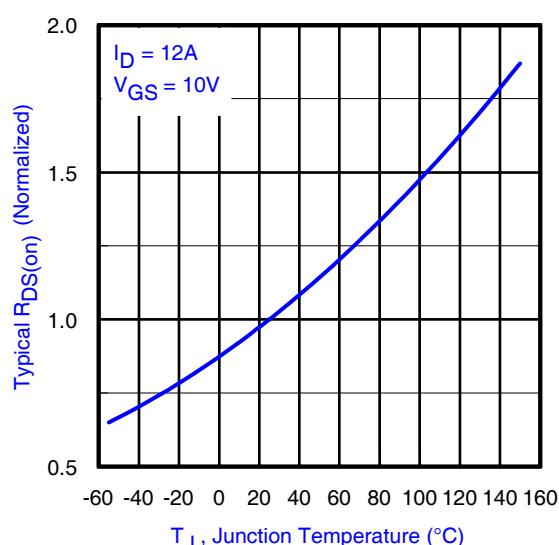


Fig 7. Normalized On-Resistance vs. Temperature

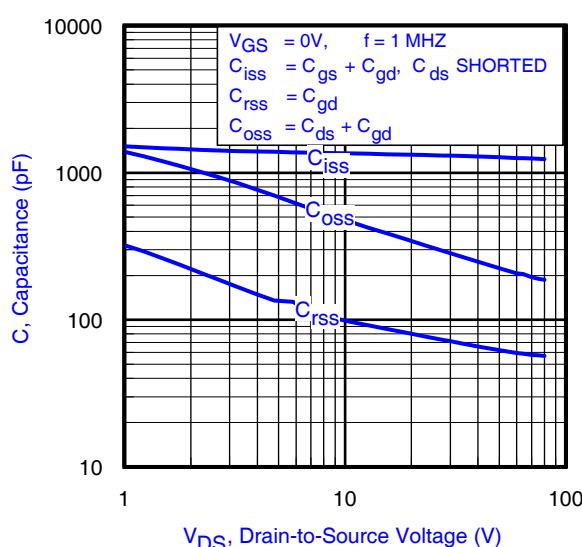


Fig 8. Typical Capacitance vs.Drain-to-Source Voltage

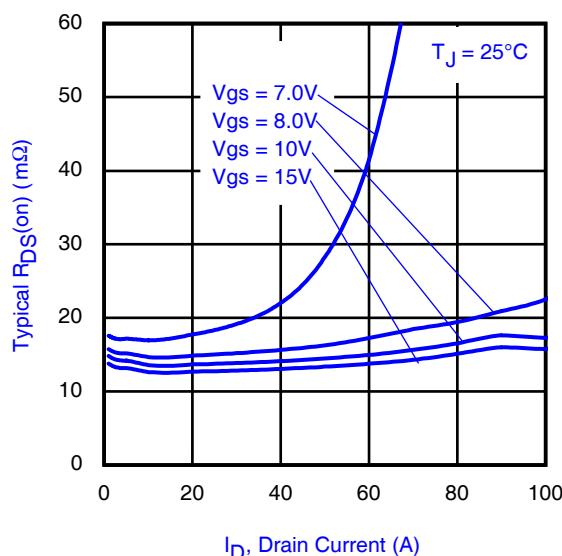


Fig 9. Typical On-Resistance vs. Drain Current

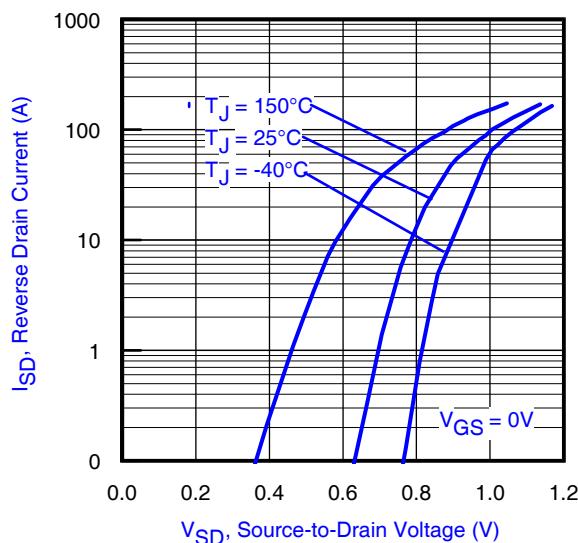


Fig 10. Typical Source-Drain Diode Forward Voltage

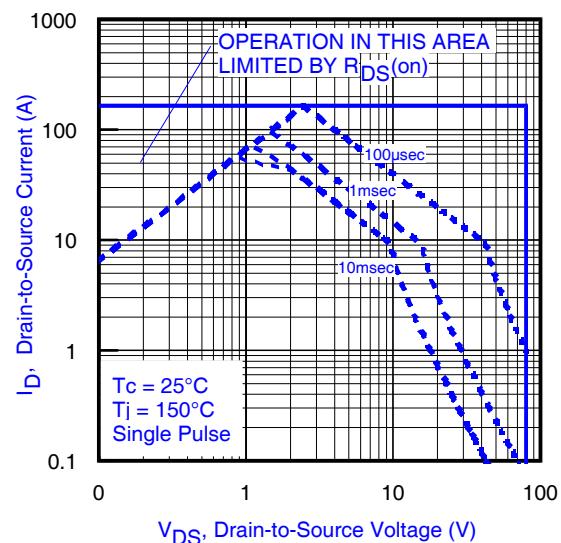


Fig 11. Maximum Safe Operating Area

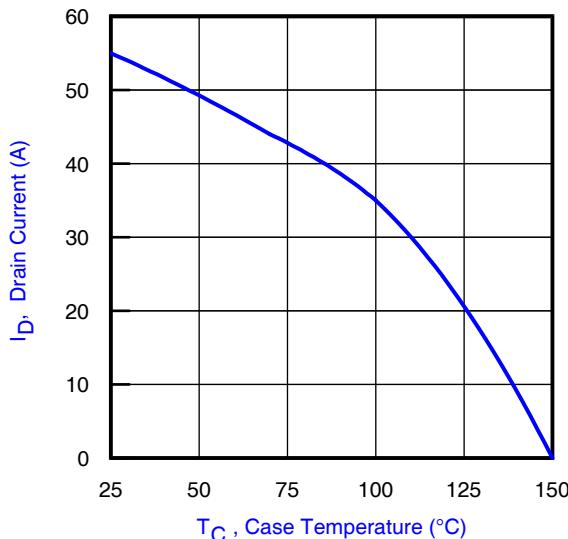


Fig 12. Maximum Drain Current vs. Case Temperature

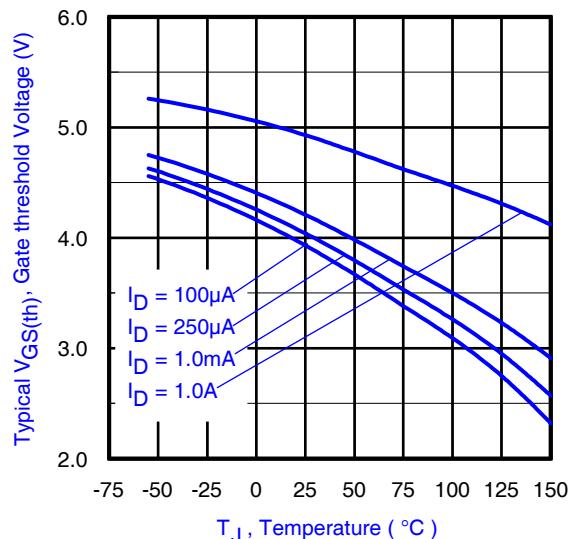


Fig 13. Threshold Voltage vs. Temperature

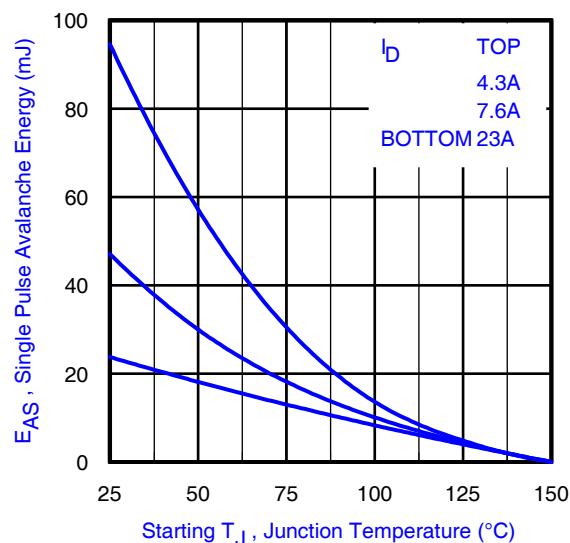


Fig 14. Maximum Avalanche Energy vs. Drain Current

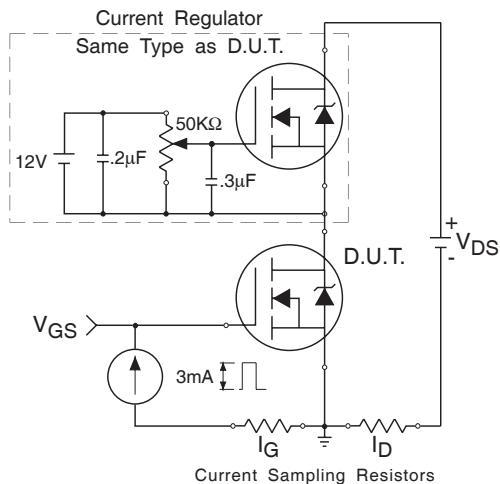


Fig 15a. Gate Charge Test Circuit

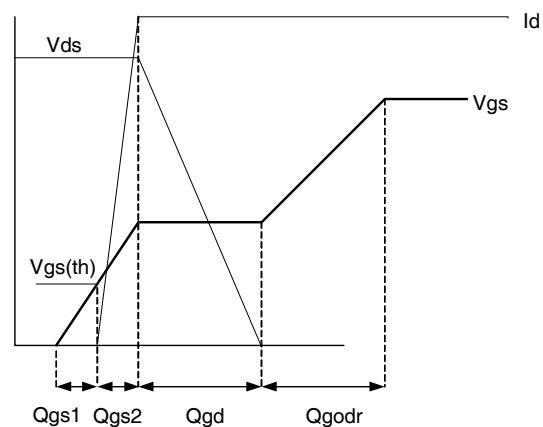


Fig 15b. Gate Charge Waveform

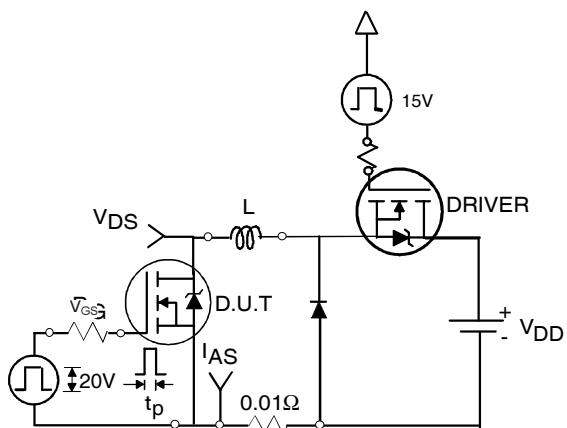


Fig 16a. Unclamped Inductive Test Circuit

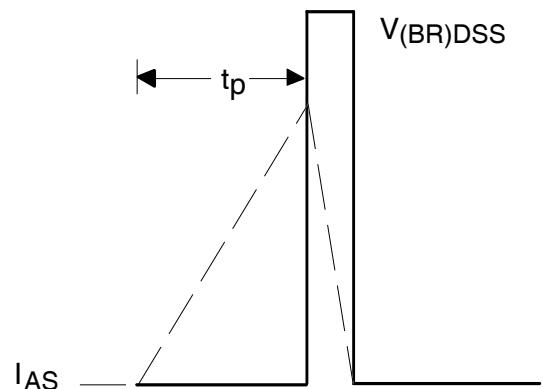


Fig 16b. Unclamped Inductive Waveforms

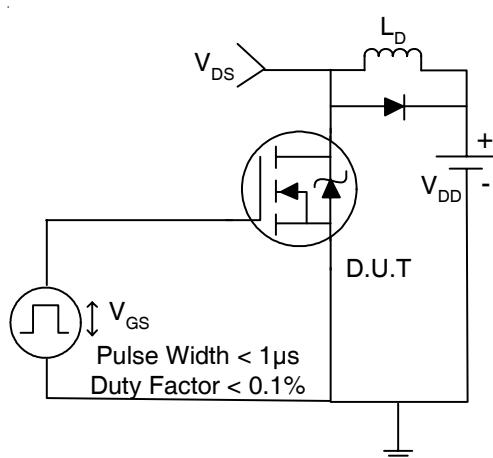


Fig 17a. Switching Time Test Circuit

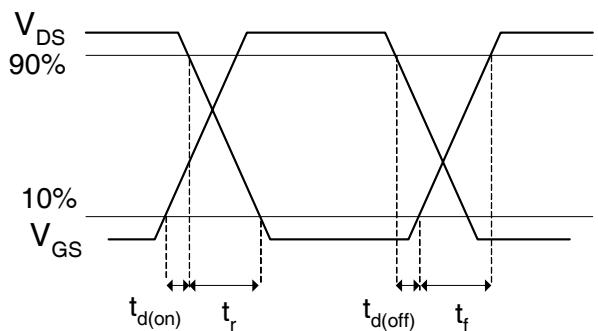


Fig 17b. Switching Time Waveforms

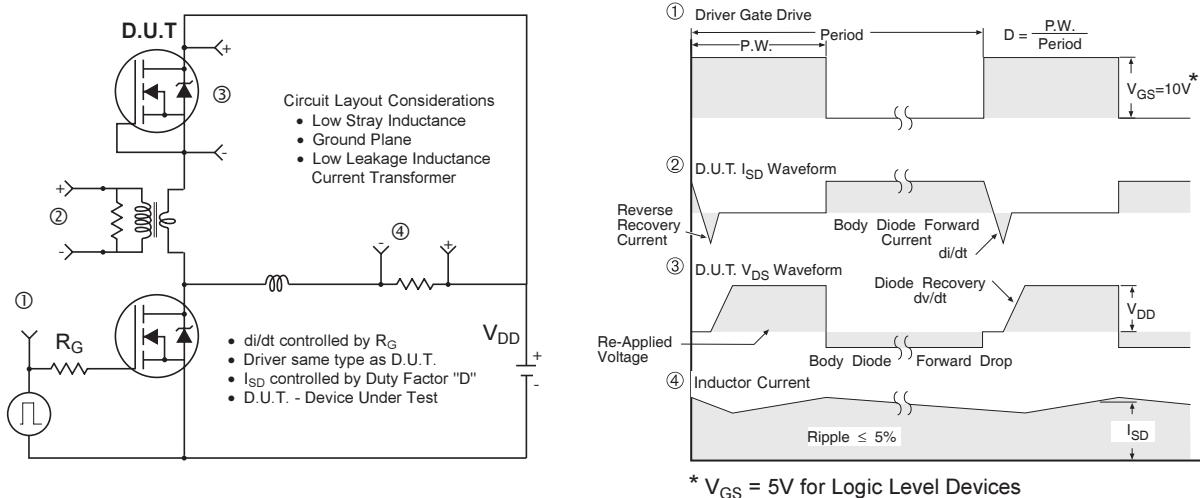
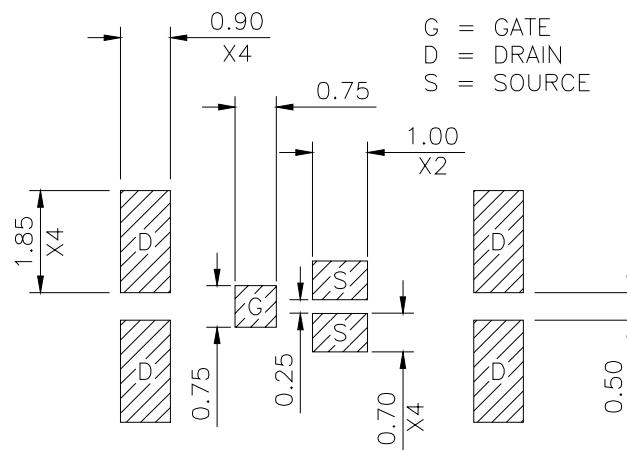
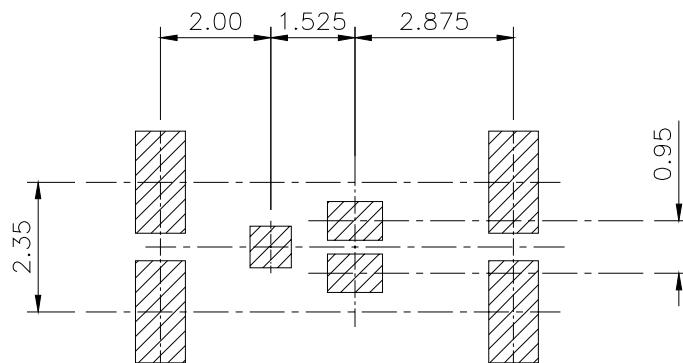


Fig 18. Diode Reverse Recovery Test Circuit for N-Channel HEXFET® Power MOSFETs

DirectFET™ Substrate and PCB Layout, MZ Outline (Medium Size Can, Z-Designation).

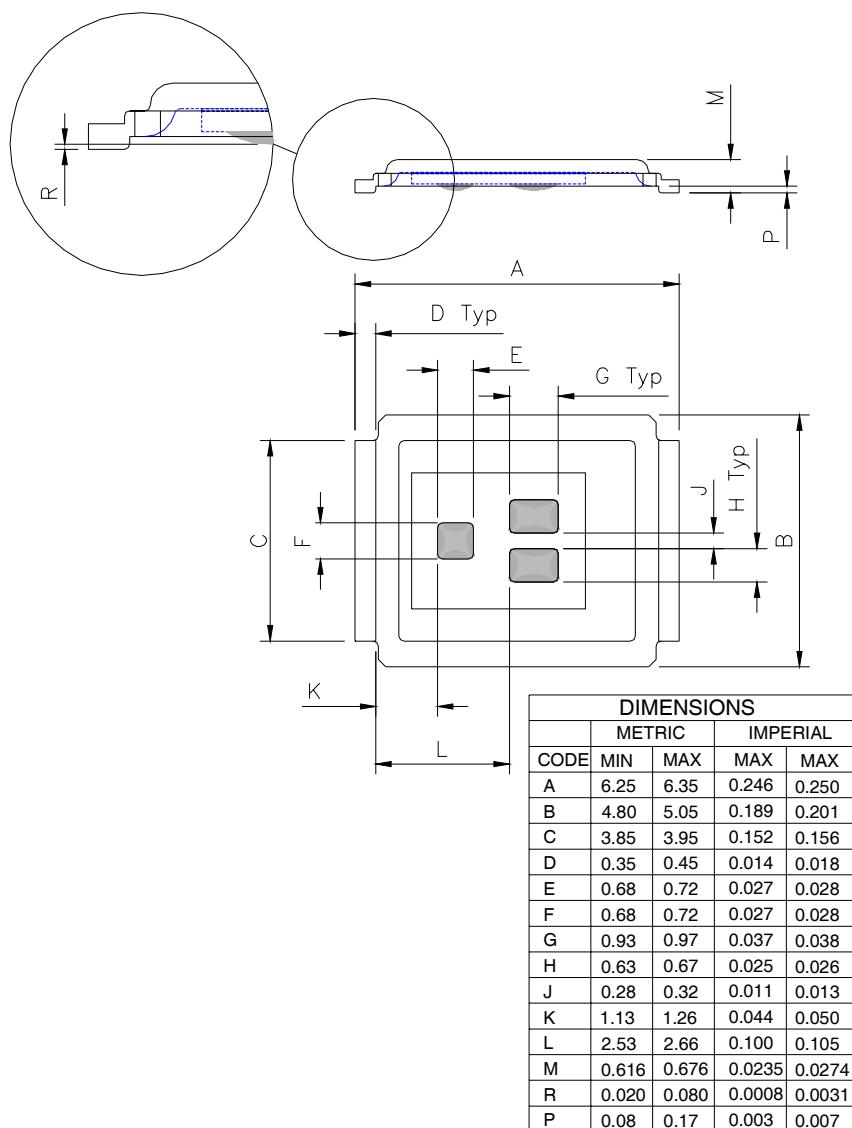
Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET.

This includes all recommendations for stencil and substrate designs.

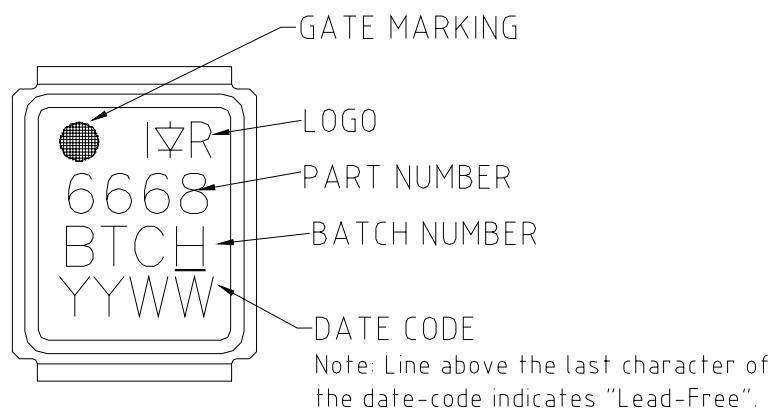


DirectFET™ Outline Dimension, MZ Outline (Medium Size Can, Z-Designation).

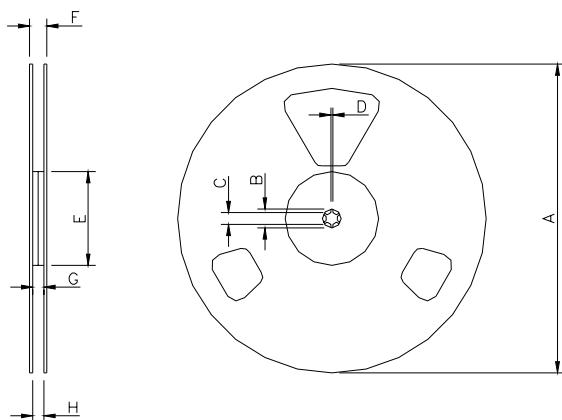
Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET.
This includes all recommendations for stencil and substrate designs.



DirectFET™ Part Marking



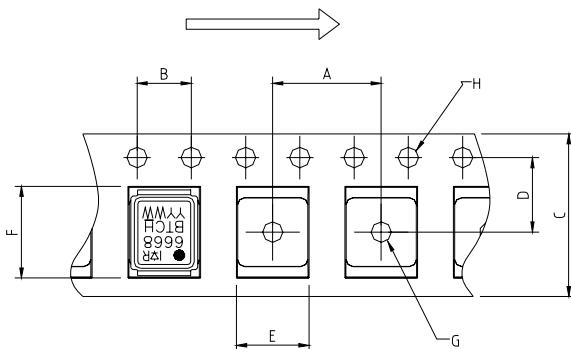
DirectFET™ Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm
Std reel quantity is 4800 parts. (ordered as IRF6668TRPBF). For 1000 parts on 7" reel, order IRF6668TR1PBF

CODE	REEL DIMENSIONS			
	STANDARD OPTION (QTY 4800)		TR1 OPTION (QTY 1000)	
	METRIC	IMPERIAL	METRIC	IMPERIAL
A	330.0	N.C.	12.992	N.C.
B	20.2	N.C.	0.795	N.C.
C	12.8	13.2	0.504	0.520
D	1.5	N.C.	0.059	N.C.
E	100.0	N.C.	3.937	N.C.
F	N.C.	18.4	N.C.	0.724
G	12.4	14.4	0.488	0.567
H	11.9	15.4	0.469	0.606

LOADED TAPE FEED DIRECTION



CODE	DIMENSIONS	
	METRIC	IMPERIAL
A	7.90	8.10
B	3.90	4.10
C	11.90	12.30
D	5.45	5.55
E	5.10	5.30
F	6.50	6.70
G	1.50	N.C.
H	1.50	1.60

Data and specifications subject to change without notice.
This product has been designed and qualified for the Consumer market.
Qualification Standards can be found on IR's Web site.

International
IR Rectifier

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Visit us at www.irf.com for sales contact information.08/06

Note: For the most current drawings please refer to the IR website at:
<http://www.irf.com/package/>